

Search Notes

Application/Control No.

10/803,183

Examiner

Hien N. Nguyen

Applicant(s)/Patent under
Reexamination

CHEN ET AL.

Art Unit

2824

SEARCHED

Class	Subclass	Date	Examiner
365	185.17	7/25/2005	HN
365	185.29		
365	185.33		
257	314		
257	315		
257	316		
257	317		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST	7/25/2005	HN